



ALPHA & OMEGA
SEMICONDUCTOR

AOH3254

150V N-Channel MOSFET

General Description

- Trench Power MV MOSFET technology
- Low $R_{DS(ON)}$
- Low Gate Charge
- Optimized for fast-switching applications

Product Summary

V_{DS}	150V
I_D (at $V_{GS}=10V$)	5A
$R_{DS(ON)}$ (at $V_{GS}=10V$)	< 63mΩ
$R_{DS(ON)}$ (at $V_{GS}=4.5V$)	< 77mΩ

Applications

- Synchronous Rectification in DC/DC and AC/DC Converters
- Industrial and Motor Drive applications

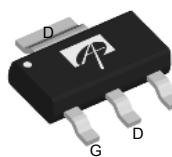
100% UIS Tested

100% Rg Tested

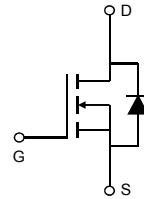
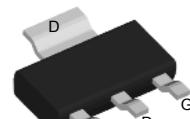


SOT223

Top View



Bottom View



Orderable Part Number

Package Type

Form

Minimum Order Quantity

AOH3254

SOT223

Tape & Reel

2500

Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	150	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current	I_D	5	A
$T_A=70^\circ C$		4	
Pulsed Drain Current ^C	I_{DM}	20	
Avalanche Current ^C	I_{AS}	15	A
Avalanche energy L=0.3mH ^C	E_{AS}	34	mJ
V_{DS} Spike	10μs	V_{SPIKE}	V
	$T_A=25^\circ C$	4.1	W
Power Dissipation ^B	P_D	2.6	
$T_A=70^\circ C$		-55 to 150	°C
Junction and Storage Temperature Range	T_J, T_{STG}		

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A $t \leq 10s$	$R_{\theta JA}$	25	30	°C/W
Maximum Junction-to-Ambient ^{A,D} Steady-State		50	60	°C/W
Maximum Junction-to-Lead Steady-State	$R_{\theta JL}$	10	15	°C/W

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	150			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=150\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$		1	5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm20\text{V}$			±100	nA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1.7	2.15	2.7	V
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=5\text{A}$ $T_J=125^\circ\text{C}$		52	63	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=2\text{A}$		102	123	
g_{FS}	Forward Transconductance	$V_{DS}=5\text{V}, I_D=5\text{A}$		60	77	$\text{m}\Omega$
V_{SD}	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.72	1	V
I_S	Maximum Body-Diode Continuous Current				5	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=75\text{V}, f=1\text{MHz}$		675		pF
C_{oss}	Output Capacitance			78		pF
C_{rss}	Reverse Transfer Capacitance			4		pF
R_g	Gate resistance	$f=1\text{MHz}$	1.4	2.9	4.4	Ω
SWITCHING PARAMETERS						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=75\text{V}, I_D=5\text{A}$		11.5	20	nC
$Q_g(4.5\text{V})$	Total Gate Charge			5.5	10	nC
Q_{gs}	Gate Source Charge			2		nC
Q_{gd}	Gate Drain Charge			2.5		nC
$t_{D(\text{on})}$	Turn-On Delay Time	$V_{GS}=10\text{V}, V_{DS}=75\text{V}, R_L=15\Omega,$ $R_{\text{GEN}}=3\Omega$		6		ns
t_r	Turn-On Rise Time			3		ns
$t_{D(\text{off})}$	Turn-Off Delay Time			20		ns
t_f	Turn-Off Fall Time			5		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=5\text{A}, dI/dt=500\text{A}/\mu\text{s}$		37		ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=5\text{A}, dI/dt=500\text{A}/\mu\text{s}$		210		nC

A. The value of R_{QJA} is measured with the device mounted on 1in^2 FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25^\circ \text{C}$. The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on $T_{J(\text{MAX})}=150^\circ \text{C}$, using $\leq 10\text{s}$ junction-to-ambient thermal resistance.

C. Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})}=150^\circ \text{C}$. Ratings are based on low frequency and duty cycles to keep initial $T_J=25^\circ \text{C}$.

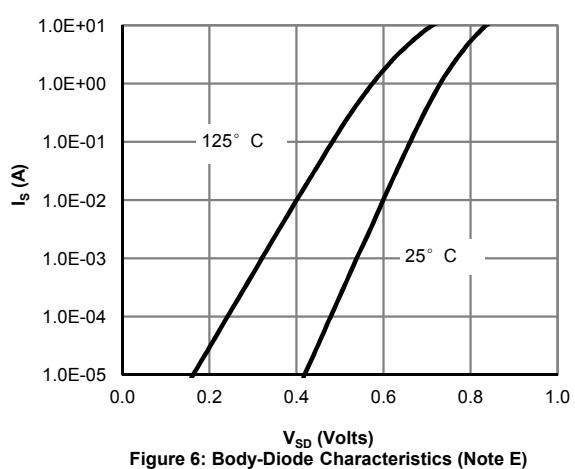
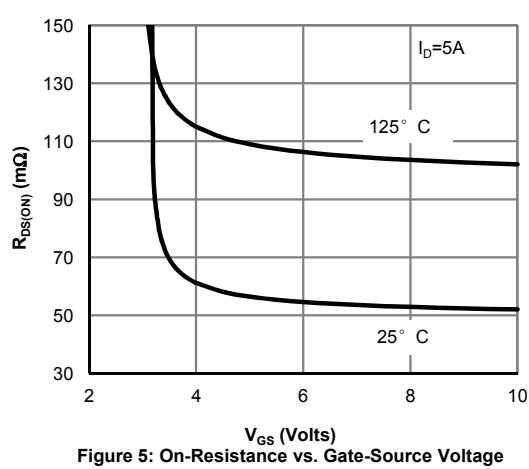
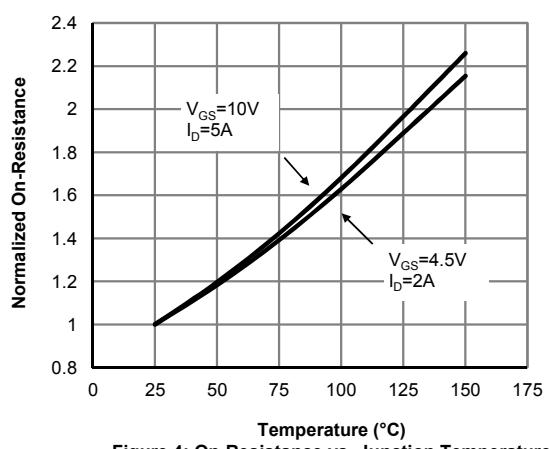
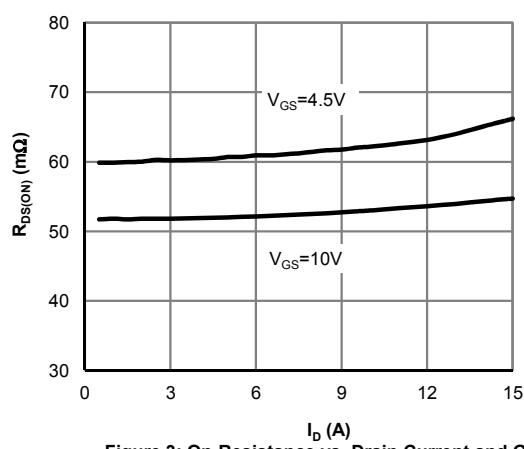
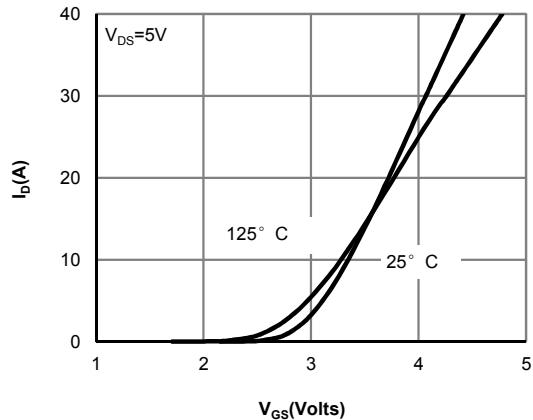
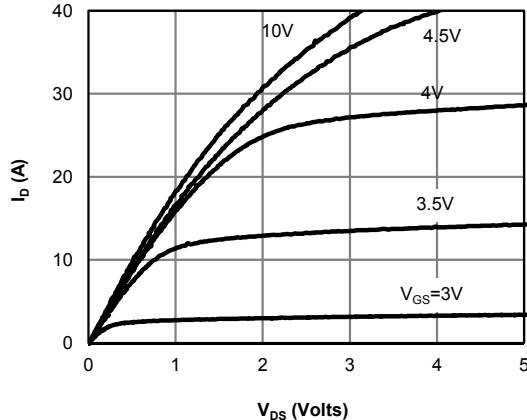
D. The R_{QJA} is the sum of the thermal impedance from junction to lead R_{QJL} and lead to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using $<300\mu\text{s}$ pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in^2 FR-4 board with 2oz. Copper, assuming a maximum junction temperature of $T_{J(\text{MAX})}=150^\circ \text{C}$. The SOA curve provides a single pulse rating.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



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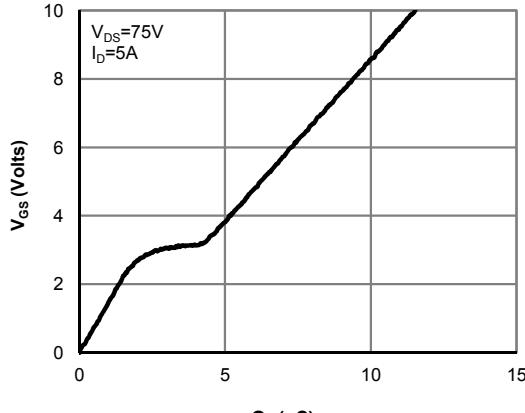


Figure 7: Gate-Charge Characteristics

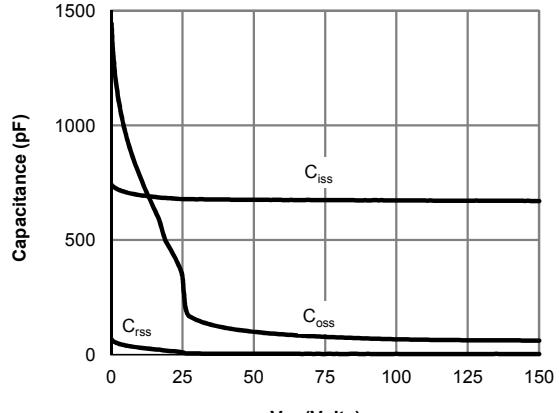


Figure 8: Capacitance Characteristics

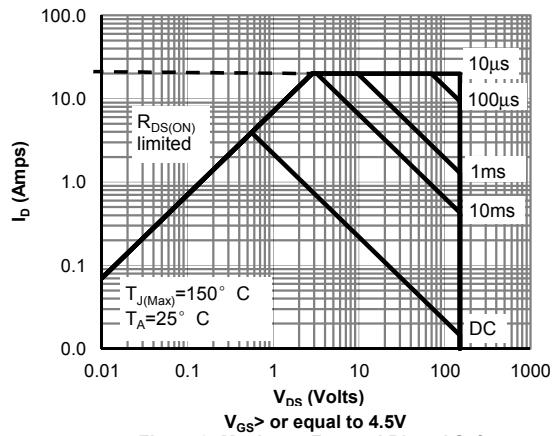


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

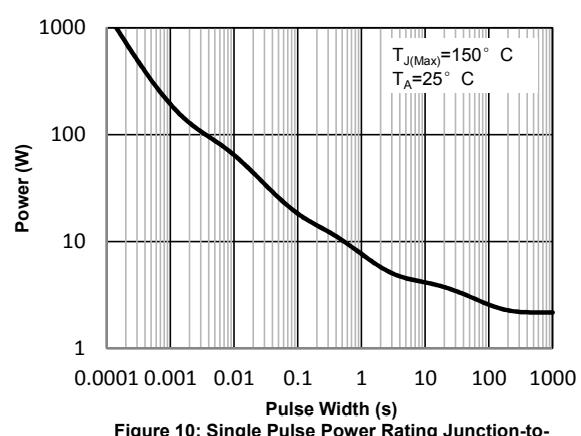


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)

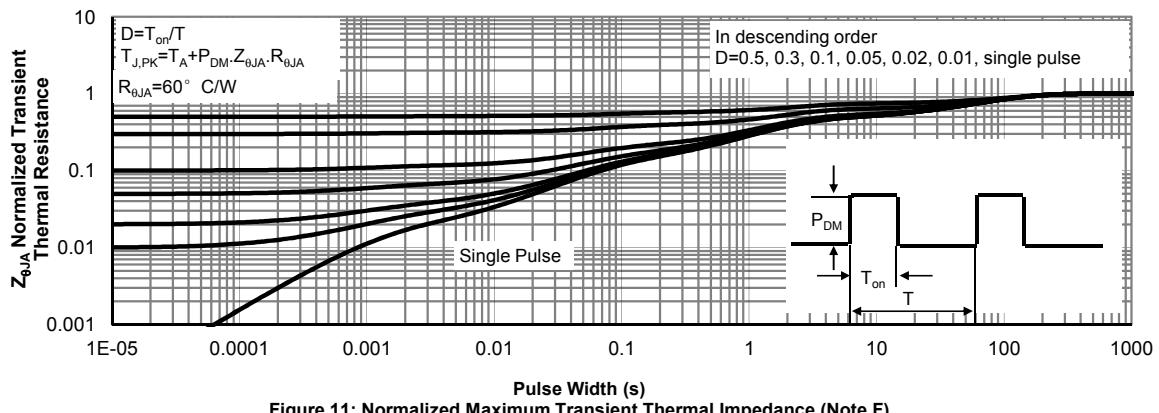
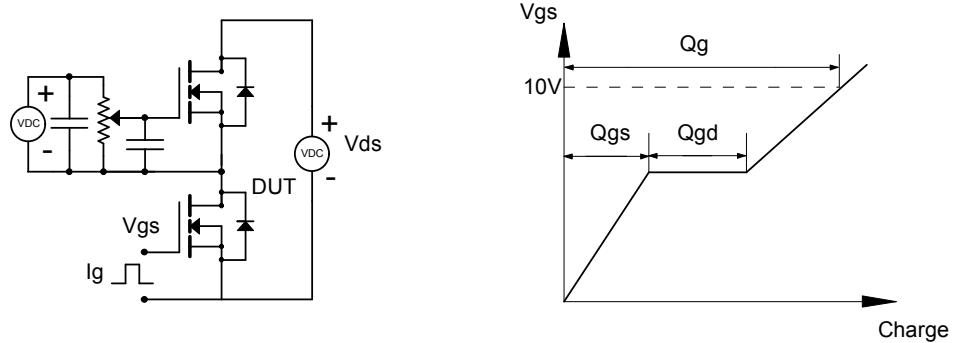
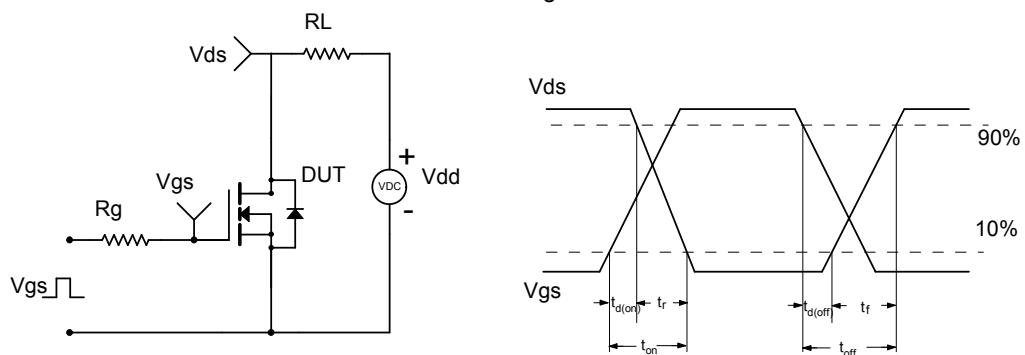


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

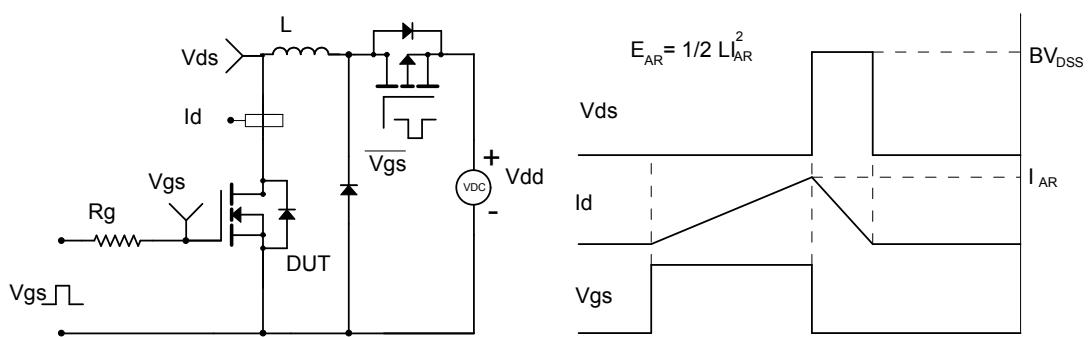
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

